

Application No.	Applicant(s)	_
09/922,488	THAYER ET AL.	
Examiner	Art Unit	
Patrick J. Nolan	1644	

SEARCHED					
Class	Subclass	Date	Examiner		
530	395	3/22/04	PN		
	403				
-	853				
424	185.1				
	192.1				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
SEQ ID	No. 2	3/22/2004	PN		
530	395, 403				
530	853				
424/185.1, 192.1					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor search, SEQ ID NO. 2, considered 60/222,184 and 60/260,512	3/22/2004	PN	